

Search Notes

Application/Control No.

10/706,651

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

ARONSON ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	88,92,93,9 4	2/27/2006	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached updated EAST search history	2/27/2006	JDS
IEEE and INSPEC: optical, housing, lens, facets parallel, TOSA, ROSA	2/27/2006	JDS